



**P-Channel Enhancement Mode Field Effect Transistor**

● **Features**

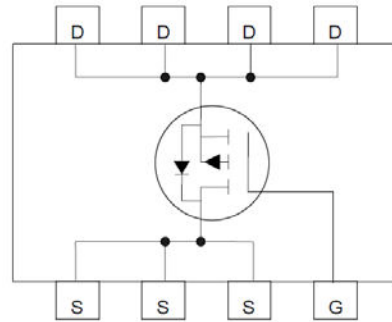
$V_{DS}$  (V) = -30V

$I_D$  = -6.5A ( $V_{GS}$  = -10V)

$R_{DS(ON)}$  < 40m $\Omega$  ( $V_{GS}$  = -10V)

$R_{DS(ON)}$  < 50m $\Omega$  ( $V_{GS}$  = -4.5V)

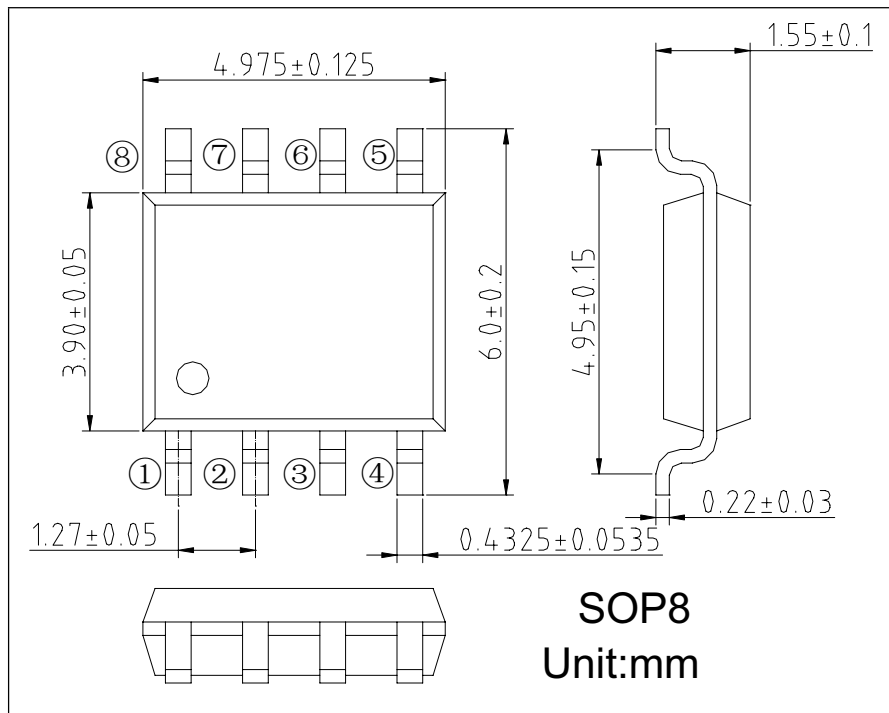
● **Pin Configurations**



● **General Description**

The HX4435 uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , and ultra-low low gate charge. This device is suitable for use as a load switch or in PWM applications. Standard Product HX4435 is Pb-free.

● **Package Information**



● **Absolute Maximum Ratings @ $T_A=25^\circ\text{C}$  unless otherwise noted**

Parameter	Symbol	Ratings	Unit
Drain-Source Voltage	$V_{DSS}$	-30	V
Gate-Source Voltage	$V_{GSS}$	$\pm 20$	V
Drain Current (Continuous) *AC	$I_D$	$T_A=25^\circ\text{C}$	-6.5
		$T_A=70^\circ\text{C}$	-5.3



Drain Current (Pulse) *B		$I_{DM}$	-30	A
Power Dissipation	$T_A=25^\circ\text{C}$	$P_D$	3	W
	$T_A=70^\circ\text{C}$		2.1	
Operating Temperature/ Storage Temperature		$T_{JJ}/T_{STG}$	-55~150	$^\circ\text{C}$

● **Electrical Characteristics** @ $T_A=25^\circ\text{C}$  unless otherwise noted

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
<b>Static</b>						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = -250\mu\text{A}$	-30	--	--	V
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = -30V, V_{GS} = 0V$	--	--	-1	$\mu\text{A}$
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{GS} = V_{DS}, I_{DS} = -250\mu\text{A}$	-1.2	-1.4	-2.7	V
Gate Leakage Current	$I_{GSS}$	$V_{GS} = \pm 20V, V_{DS} = 0V$	--	--	100	nA
Drain-Source On-state Resistance	$R_{DS(on)}$	$V_{GS} = -10V, I_D = -5.7A$	--	30	40	m $\Omega$
		$V_{GS} = -4.5V, I_D = -4.4A$	--	38	50	m $\Omega$
Forward Transconductance	$g_{FS}$	$V_{DS} = -5V, I_D = -5.7A$	--	11	--	S
Diode Forward Voltage	$V_{SD}$	$I_{SD} = -2.3A, V_{GS} = 0V$	--	-0.82	-1.2	V
Maximum Body-Diode Continuous Current	$I_S$		--	--	-2.3	A
<b>Switching</b>						
Total Gate Charge	$Q_g$	$V_{GS} = -10V, V_{DS} = -15V,$ $I_D = -6A$	--	18.3	23.79	nC
Gate-Source Charge	$Q_{gs}$		--	2.4	3.12	nC
Gate-Drain Charge	$Q_{gd}$		--	3.1	4.03	nC
Turn-on Delay Time	$t_{d(on)}$	$V_{GS} = -10V, V_{DS} = -15V,$	--	12.4	24.8	ns
Turn-off Delay Time	$t_{d(off)}$	$R_L = 15\Omega, R_{GEN} = 6\Omega$	--	41.1	82.2	ns
<b>Dynamic</b>						
Input Capacitance	$C_{iss}$	$V_{GS} = 0V, V_{DS} = -15V,$ $f = 1\text{MHz}$	--	971.5	--	pF
Output Capacitance	$C_{oss}$		--	235.1	--	pF
Reverse Transfer Capacitance	$C_{rss}$		--	82.7	--	pF

A: The value of  $R_{\theta JA}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The value in any given application depends on the user's specific board design.

B: Repetitive rating, pulse width limited by junction temperature.

C: The current rating is based on the  $\leq 10\text{s}$  junction to ambient thermal resistance rating.



● TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

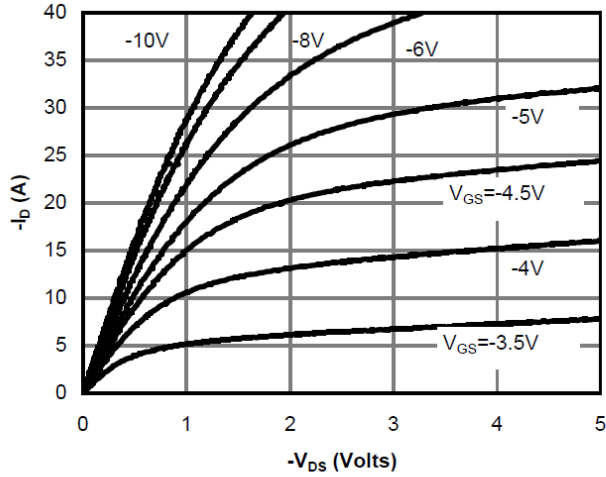


Fig 1: On-Region Characteristics

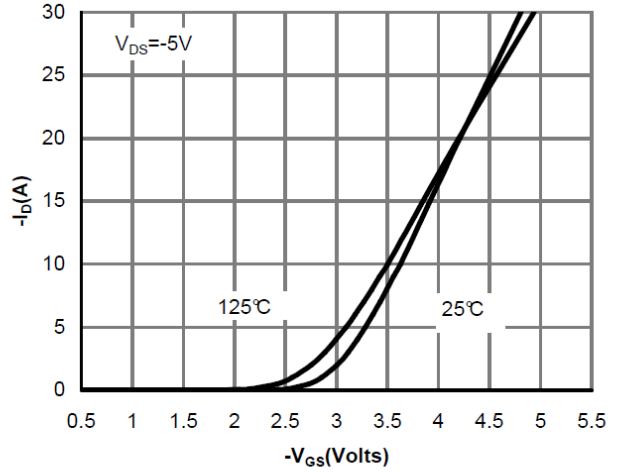


Figure 2: Transfer Characteristics

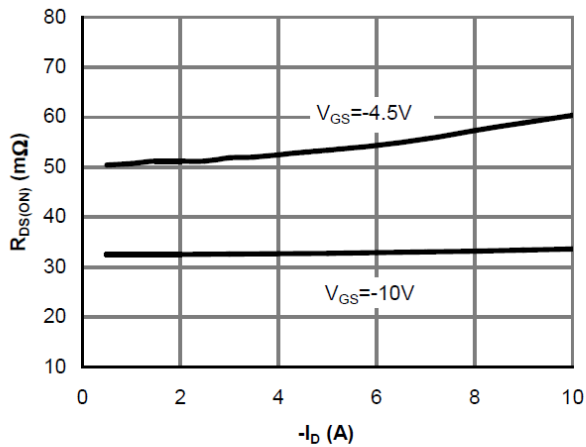


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

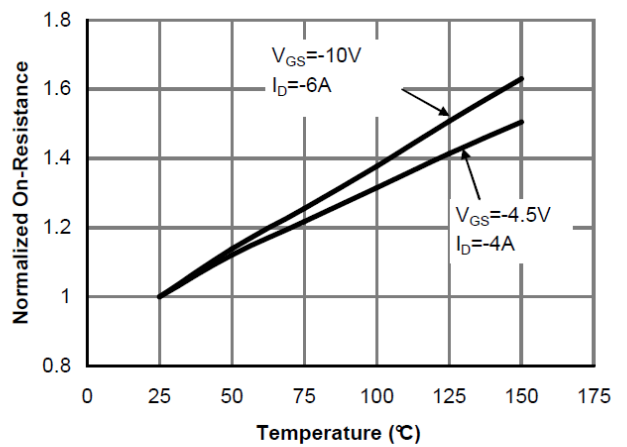


Figure 4: On-Resistance vs. Junction Temperature

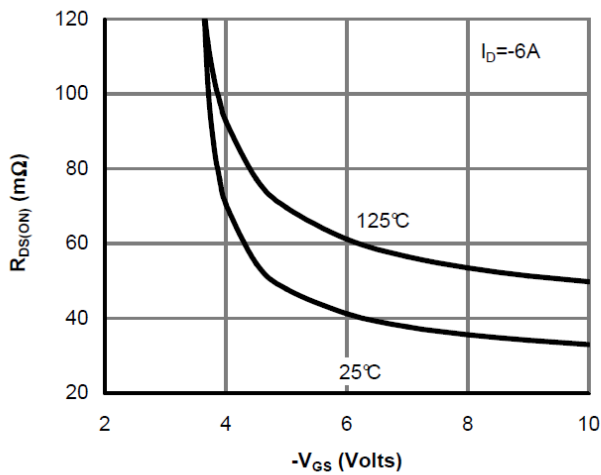


Figure 5: On-Resistance vs. Gate-Source Voltage

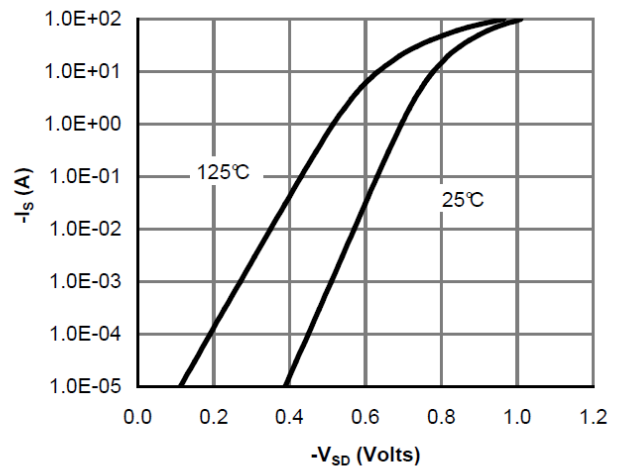


Figure 6: Body-Diode Characteristics

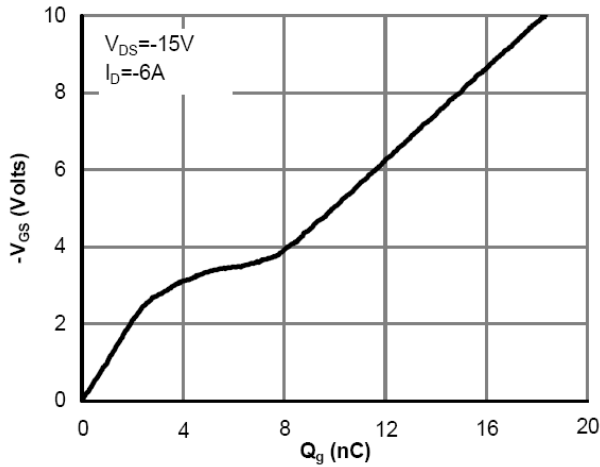


Figure 7: Gate-Charge Characteristics

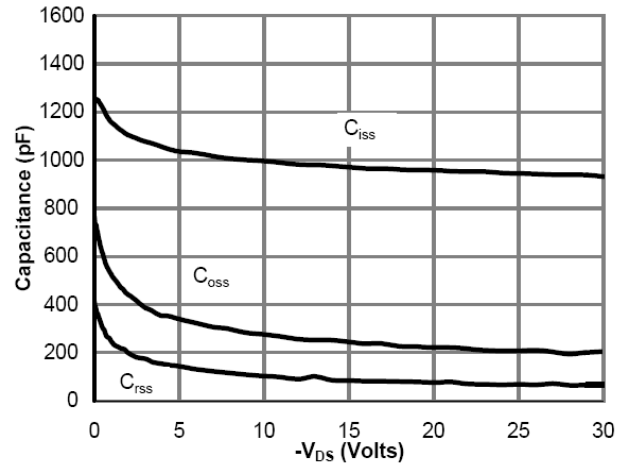


Figure 8: Capacitance Characteristics

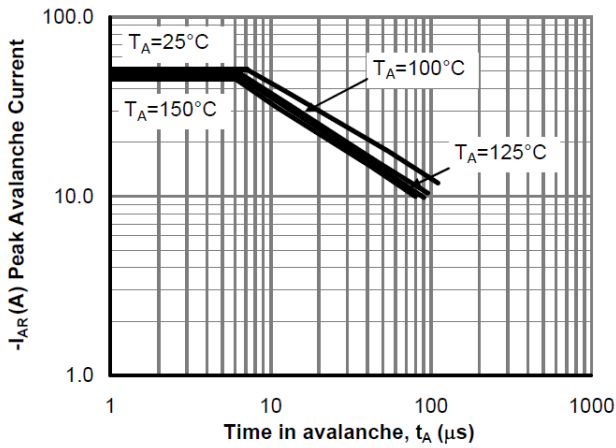


Figure 9: Single Pulse Avalanche capability

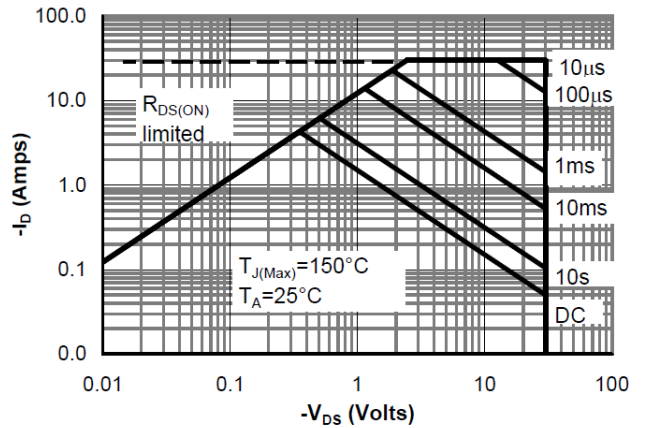


Figure 10: Maximum Forward Biased Safe Operating Area

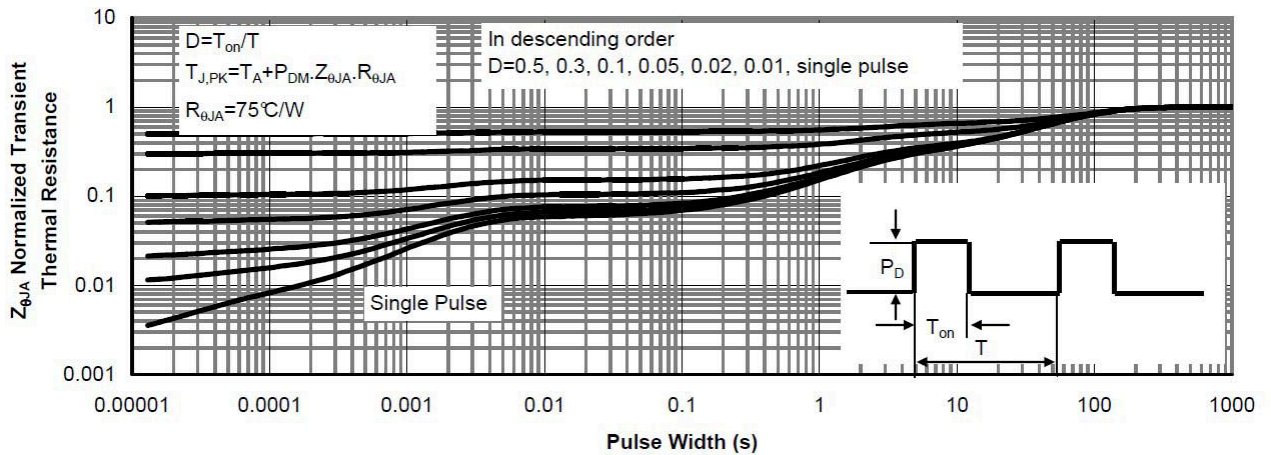


Figure 11: Normalized Maximum Transient Thermal Impedance



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